Contents

1 Light Microscopy *1*
1.1 Optical Principles *1*
1.1.1 Image Formation *1*
1.1.2 Resolution *3*
1.1.2.1 Effective Magnification *5*
1.1.2.2 Brightness and Contrast *5*
1.1.3 Depth of Field *6*
1.1.4 Aberrations *7*
1.2 Instrumentation *9*
1.2.1 Illumination System *9*
1.2.2 Objective Lens and Eyepiece *13*
1.2.2.1 Steps for Optimum Resolution *15*
1.2.2.2 Steps to Improve Depth of Field *15*
1.3 Specimen Preparation *15*
1.3.1 Sectioning *16*
1.3.1.1 Cutting *16*
1.3.1.2 Microtomy *17*
1.3.2 Mounting *17*
1.3.3 Grinding and Polishing *19*
1.3.3.1 Grinding *19*
1.3.3.2 Polishing *21*
1.3.4 Etching *23*
1.4 Imaging Modes *26*
1.4.1 Bright-Field and Dark-Field Imaging *26*
1.4.2 Phase-Contrast Microscopy *27*
1.4.3 Polarized-Light Microscopy *30*
1.4.4 Nomarski Microscopy *35*
1.4.5 Fluorescence Microscopy *37*
1.5 Confocal Microscopy *39*
1.5.1 Working Principles *39*
1.5.2 Three-Dimensional Images *41*

References 45
Further Reading 45

2 X-Ray Diffraction Methods *47*
2.1 X-Ray Radiation *47*
2.1.1 Generation of X-Rays *47*
2.1.2 X-Ray Absorption *50*
2.2 Theoretical Background of Diffraction *52*
2.2.1 Diffraction Geometry *52*
2.2.1.1 Bragg's Law *52*
2.2.1.2 Reciprocal Lattice *53*
2.2.1.3 Ewald Sphere *55*
2.2.2 Diffraction Intensity *58*
2.2.2.1 Structure Extinction *60*
2.3 X-Ray Diffractometry *62*
2.3.1 Instrumentation *62*
2.3.1.1 System Aberrations *64*
2.3.2 Samples and Data Acquisition *65*
2.3.2.1 Sample Preparation *65*
2.3.2.2 Acquisition and Treatment of Diffraction Data *65*
2.3.3 Distortions of Diffraction Spectra *67*
2.3.3.1 Preferential Orientation *67*
2.3.3.2 Crystallite Size *68*
2.3.3.3 Residual Stress *69*
2.3.4 Applications *70*
2.3.4.1 Crystal-Phase Identification *70*
2.3.4.2 Quantitative Measurement *72*
2.4 Wide-Angle X-Ray Diffraction and Scattering *75*
2.4.1 Wide-Angle Diffraction *76*
2.4.2 Wide-Angle Scattering *79*
References *82*
Further Reading *82*

3 Transmission Electron Microscopy *83*
3.1 Instrumentation *83*
3.1.1 Electron Sources *84*
3.1.1.1 Thermionic Emission Gun *85*
3.1.1.2 Field Emission Gun *86*
3.1.2 Electromagnetic Lenses *87*
3.1.3 Specimen Stage *89*
3.2 Specimen Preparation *90*
3.2.1 Prethinning *91*
3.2.2 Final Thinning *91*
3.2.2.1 Electrolytic Thinning *91*
3.2.2.2 Ion Milling *92*

3.2.2.3 Ultramicrotomy *93*
3.3 Image Modes *94*
3.3.1 Mass–Density Contrast *95*
3.3.2 Diffraction Contrast *96*
3.3.3 Phase Contrast *101*
3.3.3.1 Theoretical Aspects *102*
3.3.3.2 Two-Beam and Multiple-Beam Imaging *105*
3.4 Selected-Area Diffraction (SAD) *107*
3.4.1 Selected-Area Diffraction Characteristics *107*
3.4.2 Single-Crystal Diffraction *109*
3.4.2.1 Indexing a Cubic Crystal Pattern *109*
3.4.2.2 Identification of Crystal Phases *112*
3.4.3 Multicrystal Diffraction *114*
3.4.4 Kikuchi Lines *114*
3.5 Images of Crystal Defects *117*
3.5.1 Wedge Fringe *117*
3.5.2 Bending Contours *120*
3.5.3 Dislocations *122*
References *126*
Further Reading *126*

4 Scanning Electron Microscopy *127*
4.1 Instrumentation *127*
4.1.1 Optical Arrangement *127*
4.1.2 Signal Detection *129*
4.1.2.1 Detector *130*
4.1.3 Probe Size and Current *131*
4.2 Contrast Formation *135*
4.2.1 Electron–Specimen Interactions *135*
4.2.2 Topographic Contrast *137*
4.2.3 Compositional Contrast *139*
4.3 Operational Variables *141*
4.3.1 Working Distance and Aperture Size *141*
4.3.2 Acceleration Voltage and Probe Current *144*
4.3.3 Astigmatism *145*
4.4 Specimen Preparation *145*
4.4.1 Preparation for Topographic Examination *146*
4.4.1.1 Charging and Its Prevention *147*
4.4.2 Preparation for Microcomposition Examination *149*
4.4.3 Dehydration *149*
4.5 Electron Backscatter Diffraction *151*
4.5.1 EBSD Pattern Formation *151*
4.5.2 EBSD Indexing and Its Automation *153*
4.5.3 Applications of EBSD *155*
4.6 Environmental SEM *156*

4.6.1 ESEM Working Principle *156*
4.6.2 Applications *158*
References *160*
Further Reading *160*

5 Scanning Probe Microscopy *163*
5.1 Instrumentation *163*
5.1.1 Probe and Scanner *165*
5.1.2 Control and Vibration Isolation *165*
5.2 Scanning Tunneling Microscopy *166*
5.2.1 Tunneling Current *166*
5.2.2 Probe Tips and Working Environments *167*
5.2.3 Operational Modes *168*
5.2.4 Typical Applications *169*
5.3 Atomic Force Microscopy *170*
5.3.1 Near-Field Forces *170*
5.3.1.1 Short-Range Forces *171*
5.3.1.2 van der Waals Forces *171*
5.3.1.3 Electrostatic Forces *171*
5.3.1.4 Capillary Forces *172*
5.3.2 Force Sensors *172*
5.3.3 Operational Modes *174*
5.3.3.1 Static Contact Modes *176*
5.3.3.2 Lateral Force Microscopy *177*
5.3.3.3 Dynamic Operational Modes *177*
5.3.4 Typical Applications *180*
5.3.4.1 Static Mode *180*
5.3.4.2 Dynamic Noncontact Mode *181*
5.3.4.3 Tapping Mode *182*
5.3.4.4 Force Modulation *183*
5.4 Image Artifacts *183*
5.4.1 Tip *183*
5.4.2 Scanner *185*
5.4.3 Vibration and Operation *187*
References *189*
Further Reading *189*

6 X-Ray Spectroscopy for Elemental Analysis *191*
6.1 Features of Characteristic X-Rays *191*
6.1.1 Types of Characteristic X-Rays *193*
6.1.1.1 Selection Rules *193*
6.1.2 Comparison of K, L, and M Series *194*
6.2 X-Ray Fluorescence Spectrometry *196*
6.2.1 Wavelength Dispersive Spectroscopy *199*
6.2.1.1 Analyzing Crystal *200*

6.2.1.2 Wavelength Dispersive Spectra *201*
6.2.2 Energy Dispersive Spectroscopy *203*
6.2.2.1 Detector *203*
6.2.2.2 Energy Dispersive Spectra *204*
6.2.2.3 Advances in Energy Dispersive Spectroscopy *204*
6.2.3 XRF Working Atmosphere and Sample Preparation *206*
6.3 Energy Dispersive Spectroscopy in Electron Microscopes *207*
6.3.1 Special Features *208*
6.3.2 Scanning Modes *210*
6.4 Qualitative and Quantitative Analysis *211*
6.4.1 Qualitative Analysis *211*
6.4.2 Quantitative Analysis *213*
6.4.2.1 Quantitative Analysis by X-Ray Fluorescence *214*
6.4.2.2 Fundamental Parameter Method *215*
6.4.2.3 Quantitative Analysis in Electron Microscopy *216*
References *219*
Further Reading *219*

7 Electron Spectroscopy for Surface Analysis *221*
7.1 Basic Principles *221*
7.1.1 X-Ray Photoelectron Spectroscopy *221*
7.1.2 Auger Electron Spectroscopy *222*
7.2 Instrumentation *225*
7.2.1 Ultrahigh Vacuum System *225*
7.2.2 Source Guns *227*
7.2.2.1 X-Ray Gun *227*
7.2.2.2 Electron Gun *228*
7.2.2.3 Ion Gun *229*
7.2.3 Electron Energy Analyzers *229*
7.3 Characteristics of Electron Spectra *230*
7.3.1 Photoelectron Spectra *230*
7.3.2 Auger Electron Spectra *233*
7.4 Qualitative and Quantitative Analysis *235*
7.4.1 Qualitative Analysis *235*
7.4.1.1 Peak Identification *239*
7.4.1.2 Chemical Shifts *239*
7.4.1.3 Problems with Insulating Materials *241*
7.4.2 Quantitative Analysis *246*
7.4.2.1 Peaks and Sensitivity Factors *246*
7.4.3 Composition Depth Profiling *247*
References *250*
Further Reading *251*

8 Secondary Ion Mass Spectrometry for Surface Analysis *253*
8.1 Basic Principles *253*
8.1.1 Secondary Ion Generation *254*
8.1.2 Dynamic and Static SIMS *257*
8.2 Instrumentation *258*
8.2.1 Primary Ion System *258*
8.2.1.1 Ion Sources *259*
8.2.1.2 Wien Filter *262*
8.2.2 Mass Analysis System *262*
8.2.2.1 Magnetic Sector Analyzer *263*
8.2.2.2 Quadrupole Mass Analyzer *264*
8.2.2.3 Time-of-Flight Analyzer *264*
8.3 Surface Structure Analysis *266*
8.3.1 Experimental Aspects *266*
8.3.1.1 Primary Ions *266*
8.3.1.2 Flood Gun *266*
8.3.1.3 Sample Handling *267*
8.3.2 Spectrum Interpretation *268*
8.3.2.1 Element Identification *269*
8.4 SIMS Imaging *272*
8.4.1 Generation of SIMS Images *274*
8.4.2 Image Quality *275*
8.5 SIMS Depth Profiling *275*
8.5.1 Generation of Depth Profiles *276*
8.5.2 Optimization of Depth Profiling *276*
8.5.2.1 Primary Beam Energy *278*
8.5.2.2 Incident Angle of Primary Beam *278*
8.5.2.3 Analysis Area *279*
References *282*

9 Vibrational Spectroscopy for Molecular Analysis *283*
9.1 Theoretical Background *283*
9.1.1 Electromagnetic Radiation *283*
9.1.2 Origin of Molecular Vibrations *285*
9.1.3 Principles of Vibrational Spectroscopy *286*
9.1.3.1 Infrared Absorption *286*
9.1.3.2 Raman Scattering *287*
9.1.4 Normal Mode of Molecular Vibrations *289*
9.1.4.1 Number of Normal Vibration Modes *291*
9.1.4.2 Classification of Normal Vibration Modes *291*
9.1.5 Infrared and Raman Activity *292*
9.1.5.1 Infrared Activity *293*
9.1.5.2 Raman Activity *295*
9.2 Fourier Transform Infrared Spectroscopy *297*
9.2.1 Working Principles *298*

9.2.2 Instrumentation *300*
9.2.2.1 Infrared Light Source *300*
9.2.2.2 Beamsplitter *300*
9.2.2.3 Infrared Detector *301*
9.2.2.4 Fourier Transform Infrared Spectra *302*
9.2.3 Examination Techniques *304*
9.2.3.1 Transmittance *304*
9.2.3.2 Solid Sample Preparation *304*
9.2.3.3 Liquid and Gas Sample Preparation *304*
9.2.3.4 Reflectance *305*
9.2.4 Fourier Transform Infrared Microspectroscopy *307*
9.2.4.1 Instrumentation *307*
9.2.4.2 Applications *309*
9.3 Raman Microscopy *310*
9.3.1 Instrumentation *310*
9.3.1.1 Laser Source *311*
9.3.1.2 Microscope System *311*
9.3.1.3 Prefilters *312*
9.3.1.4 Diffraction Grating *313*
9.3.1.5 Detector *314*
9.3.2 Fluorescence Problem *314*
9.3.3 Raman Imaging *315*
9.3.4 Applications *316*
9.3.4.1 Phase Identification *317*
9.3.4.2 Polymer Identification *319*
9.3.4.3 Composition Determination *319*
9.3.4.4 Determination of Residual Strain *321*
9.3.4.5 Determination of Crystallographic Orientation *322*
9.4 Interpretation of Vibrational Spectra *323*
9.4.1 Qualitative Methods *323*
9.4.1.1 Spectrum Comparison *323*
9.4.1.2 Identifying Characteristic Bands *324*
9.4.1.3 Band Intensities *327*
9.4.2 Quantitative Methods *327*
9.4.2.1 Quantitative Analysis of Infrared Spectra *327*
9.4.2.2 Quantitative Analysis of Raman Spectra *330*
References *331*
Further Reading *332*

10 Thermal Analysis *333*
10.1 Common Characteristics *333*
10.1.1 Thermal Events *333*
10.1.1.1 Enthalpy Change *335*
10.1.2 Instrumentation *335*
10.1.3 Experimental Parameters *336*

10.2 Differential Thermal Analysis and Differential Scanning Calorimetry *337*
10.2.1 Working Principles *337*
10.2.1.1 Differential Thermal Analysis *337*
10.2.1.2 Differential Scanning Calorimetry *338*
10.2.1.3 Temperature-Modulated Differential Scanning Calorimetry *340*
10.2.2 Experimental Aspects *342*
10.2.2.1 Sample Requirements *342*
10.2.2.2 Baseline Determination *343*
10.2.2.3 Effects of Scanning Rate *344*
10.2.3 Measurement of Temperature and Enthalpy Change *345*
10.2.3.1 Transition Temperatures *345*
10.2.3.2 Measurement of Enthalpy Change *347*
10.2.3.3 Calibration of Temperature and Enthalpy Change *348*
10.2.4 Applications *348*
10.2.4.1 Determination of Heat Capacity *348*
10.2.4.2 Determination of Phase Transformation and Phase Diagrams *350*
10.2.4.3 Applications to Polymers *351*
10.3 Thermogravimetry *353*
10.3.1 Instrumentation *354*
10.3.2 Experimental Aspects *355*
10.3.2.1 Samples *355*
10.3.2.2 Atmosphere *356*
10.3.2.3 Temperature Calibration *358*
10.3.2.4 Heating Rate *359*
10.3.3 Interpretation of Thermogravimetric Curves *360*
10.3.3.1 Types of Curves *360*
10.3.3.2 Temperature Determination *362*
10.3.4 Applications *362*
References *365*
Further Reading *365*

Index *367*